# Monthly LabAdviser update: 18/11 2016

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| Updated Subject  | Contributor | Link to the updated pages |
|  Ellipsometer* Dielectric function determination of new thin-film semiconductors
	+ Learning about their electronic properties
* Phase analysis of ”non-ideal” thin films
* Thickness mapping (for its own sake and for resistivity mapping)
* All-optical determination of electrical properties of transparent conductive materials
 | **Andrea Crovetto @nanotech** | <http://labadviser.danchip.dtu.dk/index.php?title=Specific_Process_Knowledge/Characterization/Optical_characterization/advanced_ellipsometry&oldid=24964>" |

# Equipment Manuals updated in LabManager:

As an approved user on a piece of equipment you have to make sure you have read and understood the latest version of the manual before using the equipment.

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| **APV and manual for fume hoods in D3 cleanroom** |
| **APV and manual for fumehoods in B-1. F-3 and C-1** |
| **Manual for LPCVD nitride furnace (6") E3** |
| **Manual for LPCVD TEOS furnace** |
| **Manual for RIE2** |
| **Manual for 7up-wafer C-1** |
| **Manual for Anneal Bond furnace (C3)** |
| **Manual for Gate Oxide furnace (A2)** |
| **Manual for Furnace: Multipurpose Annealing** |
| **Manual for SEM Supra 1** |

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